Search Notes (continued)



Application/Control No.	Applicant(s)/Patent under Reexamination
10/022,594	KAMIYA ET AL.
Examiner .	Art Unit
Shick C. Hom	2616

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
370	476, 903,	5/15/2007	SH
370	906, 907	5/15/2007	SH
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(INCLUDING		STRATEGY)		
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